LIST OF ART CITED BY APPLICANT				ATTY, DOCKET NO MRE-0045.01	APPLN. SERIAL NO. 10/825,361			
	(PTO-	1449) Julii	2 8 2004	APPLICANT(S) Ji Hyun HWAN(HWANG	G, Do Hyui	n KIM and Sa	ng Yeo	in
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				APPLICANT(S) Ji Hyun HWAN HWANG	G, Do Hyu	ın KIM and S	ang Ye	on	
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				FILING DATE April 16, 2004	GROUP 1734				
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EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.